

MOS FIELD EFFECT TRANSISTOR μ PA1851

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1851 is a switching device which can be driven directly by a 4.0-V power source.

The μ PA1851 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- Can be driven by a 4.0-V power source
- · Low on-state resistance

 $R_{DS(on)1}$ = 105 $m\Omega$ MAX. (Vgs = -10 V, Ip = -1.5 A)

 $R_{DS(on)2} = 210 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.5 \text{ V, Ip} = -1.5 \text{ A)}$

 $R_{DS(on)3} = 250 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.0 \text{ V, Ip} = -1.5 \text{ A)}$

Built-in G-S protection diode against ESD

ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1851GR-9JG	Power TSSOP8

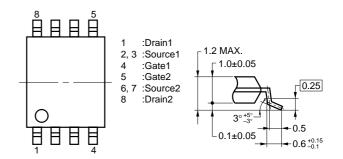
ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

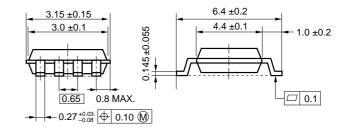
Drain to Source Voltage	Voss	-20	V
Gate to Source Voltage	Vgss	-20/+5	V
Drain Current (DC)	ID(DC)	∓2.5	Α
Drain Current (pulse) Note1	D(pulse)	∓10	Α
Total Power Dissipation Note2	PT	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1 %

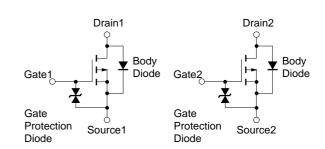
2. Mounted on ceramic substrate of 50 cm² x 1.1 mm

PACKAGE DRAWING (Unit: mm)





EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

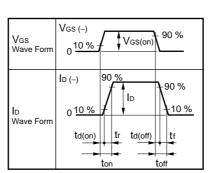
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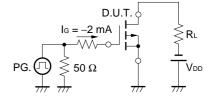
★ ELECTRICAL CHARACTERISTICS (T_A = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain Cut-off Current	Inss	V _{DS} = -20 V, V _{GS} = 0 V			-10	μΑ
Gate Leakage Current	lgss	$V_{GS} = \mp 20 \text{ V}, V_{DS} = 0 \text{ V}$			∓ 10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	$V_{DS} = -10 \text{ V}, \text{ ID} = -1 \text{ mA}$	-1.0	-1.5	-2.5	V
Forward Transfer Admittance	yfs	V _{DS} = -10 V, I _D = -1.5 A	1	3.5		S
Drain to Source On-state Resistance	RDS(on)1	V _G s = -10 V, I _D = -1.5 A		83	105	mΩ
	R _{DS(on)2}	Vgs = -4.5 V, ID = -1.5 A		141	210	mΩ
	R _{DS(on)3}	Vgs = -4.0 V, ID = -1.5 A		163	250	mΩ
Input Capacitance	Ciss	Vps = -10 V		220		pF
Output Capacitance	Coss	V _G S = 0 V		240		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		50		pF
Turn-on Delay Time	td(on)	V _{DD} = -10 V		110		ns
Rise Time	tr	ID = -2.0 A		500		ns
Turn-off Delay Time	td(off)	$V_{GS(on)} = -4.0 \text{ V}$		160		ns
Fall Time	t _f	$R_G = 10 \Omega$		310		ns
Total Gate Charge	Q _G	V _{DD} = -10 V		8.3		nC
Gate to Source Charge	Qgs	I _D = -2.5 A		2.4		nC
Gate to Drain Charge	Q _{GD}	V _{GS} = -4.0 V		4.7		nC
Diode Forward Voltage	V _F (S-D)	I _F = 2.5 A, V _{GS} = 0 V		0.82		V
Reverse Recovery Time	trr	IF = 2.5 A, Vgs = 0 V		40		ns
Reverse Recovery Charge	Qrr	di/dt = 20 A / μs		6.5		nC

★ TEST CIRCUIT 1 SWITCHING TIME

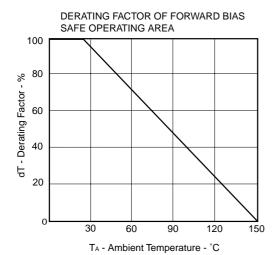


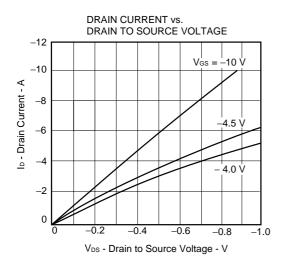
TEST CIRCUIT 2 GATE CHARGE

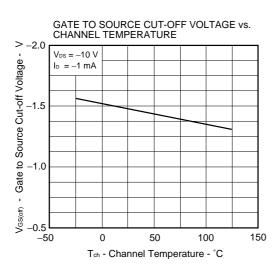


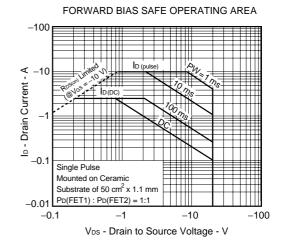


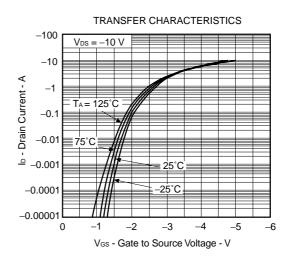
★ TYPICAL CHARACTERISTICS (T_A = 25°C)

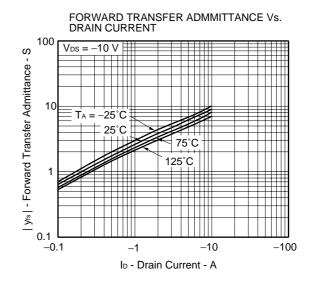




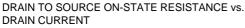


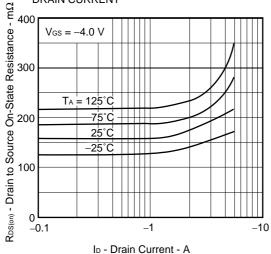




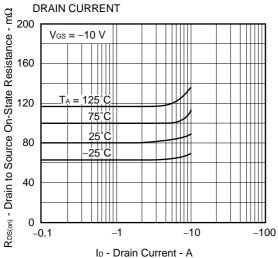


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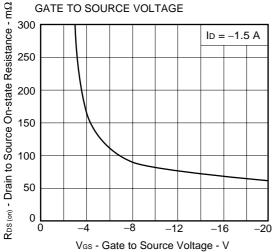




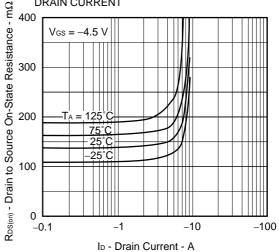
DRAIN TO SOURCE ON-STATE RESISTANCE vs.



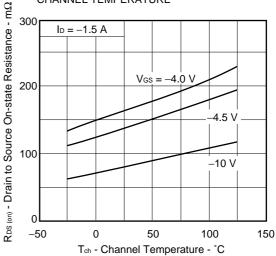
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



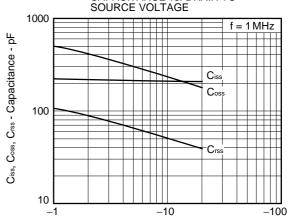
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



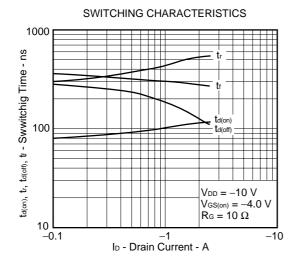
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



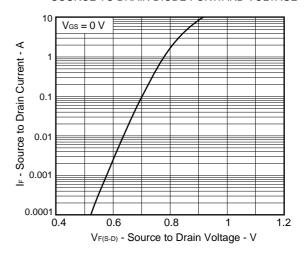
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE

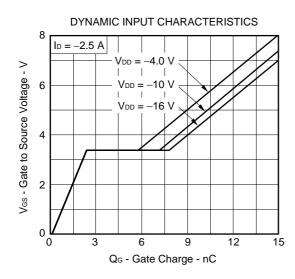


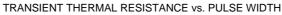
V_{DS} - Drain to Source Voltage - V

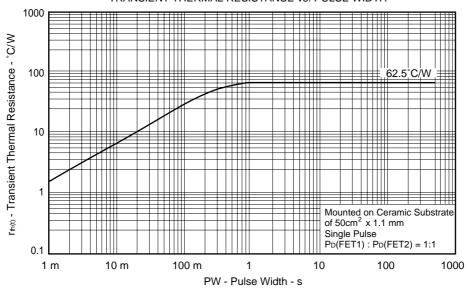


SOURCE TO DRAIN DIODE FORWARD VOLTAGE









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NEC

 μ PA1851

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